

<b>Notice of References Cited</b>	Application/Control No. 10/726,666	Applicant(s)/Patent Under Reexamination YOSHIOKA ET AL.	
	Examiner Tae H. Yoon	Art Unit 1714	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0247896 A1	12-2004	Apen et al.	428/447
*	C	US-2005/0042538 A1	02-2005	Babich et al.	430/270.1
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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